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Application/Control No.	Applicant(s)/Patent under Reexamination
10/820,421	CHIU ET AL.
Examiner	Art Unit
John Juba, Jr.	2872

SEARCHED				
Class	Subclass	Date	Examiner	
359	486	3/21/2005	IJ	
UPDATED	ABOVE	8/25/2005	IJ	
359	572	8/25/2005	IJ	
359	576	8/25/2005	JJ	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	L			

SEARCH NOT (INCLUDING SEARCH))
	DATE	EXMR
INSPEC™ search: (nanoimprint or (nano adj imprint)) and (polariz\$3 or polaris\$3)	3/21/2005	JJ
INSPEC™ search: ((wire adj grid) or (polarizer\$1 or polariser\$1) and (double adj layer)	3/21/2005	'n
EAST text search notes attached	3/21/2005	JJ
UPDATED previous EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached history	8/24/2005	າາ
Further EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) see attached history	8/25/2005	າາ